

Pb Free Plating Product

## STTH6003CW

60.0 Ampere, 300 Volt Common Cathode Fast Recovery Epitaxial Diode

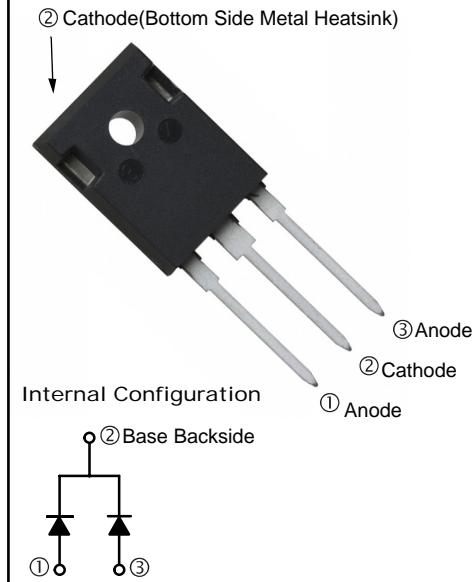
**APPLICATION**

- Freewheeling, Snubber, Clamp
- Inversion Welder
- PFC
- Plating Power Supply
- Ultrasonic Cleaner and Welder
- Converter & Chopper
- UPS

**PRODUCT FEATURE**

- Ultrafast Recovery Time
- Soft Recovery Characteristics
- Low Recovery Loss
- Low Forward Voltage
- High Surge Current Capability
- Low Leakage Current

## TO-247AD/TO-3P

**GENERAL DESCRIPTION**

STTH6003CW using the lastest FRED FAB process(planar passivation chip) with ultrafast and soft recovery characteristic.

**ABSOLUTE MAXIMUM RATINGS**T<sub>C</sub>=25°C unless otherwise specified

| Symbol               | Parameter                            | Test Conditions                          | Values      | Unit  |
|----------------------|--------------------------------------|--|-------------|-------|
| V <sub>R</sub>       | Maximum D.C. Reverse Voltage         |  | 300         | V     |
| V <sub>RRM</sub>     | Maximum Repetitive Reverse Voltage   |  | 300         | V     |
| I <sub>F(AV)</sub>   | Average Forward Current              | T <sub>C</sub> =110°C, Per Diode         | 30          | A     |
|                      |                                      | T <sub>C</sub> =110°C, Per Package       | 60          | A     |
| I <sub>F(RMS)</sub>  | RMS Forward Current                  | T <sub>C</sub> =110°C, Per Diode         | 42          | A     |
| I <sub>FSM</sub>     | Non-Repetitive Surge Forward Current | T <sub>J</sub> =45°C, t=10ms, 50Hz, Sine | 480         | A     |
| P <sub>D</sub>       | Power Dissipation                    |  | 156         | W     |
| T <sub>J</sub>       | Junction Temperature                 |  | -55 to +150 | °C    |
| T <sub>STG</sub>     | Storage Temperature Range            |  | -55 to +150 | °C    |
| Torque               | Module-to-Sink                       | Recommended (M3)                         | 1.1         | N·m   |
| R <sub>th(J-C)</sub> | Thermal Resistance                   | Junction-to-Case, Per Diode              | 0.8         | °C /W |
| Weight               |                                      |  | 6           | g     |

**ELECTRICAL CHARACTERISTICS**T<sub>C</sub>=25°C unless otherwise specified

| Symbol           | Parameter                     | Test Conditions  | Min. | Typ. | Max. | Unit |
|------------------|-------------------------------|--|------|------|------|------|
| I <sub>RM</sub>  | Reverse Leakage Current       | V <sub>R</sub> =300V   | --   | --   | 10   | µA   |
|                  |                               | V <sub>R</sub> =300V, T <sub>J</sub> =125°C  | --   | --   | 10   | mA   |
| V <sub>F</sub>   | Forward Voltage               | I <sub>F</sub> =30A  | --   | 1.25 | 1.8  | V    |
|                  |                               | I <sub>F</sub> =30A, T <sub>J</sub> =125°C   | --   | 1.12 | --   | V    |
| t <sub>rr</sub>  | Reverse Recovery Time         | I <sub>F</sub> =1A, V <sub>R</sub> =30V, dI <sub>F</sub> /dt=-200A/µs                            | --   | 22   | --   | ns   |
| t <sub>rr</sub>  | Reverse Recovery Time         | V <sub>R</sub> =150V, I <sub>F</sub> =30A<br>dI <sub>F</sub> /dt=-200A/µs, T <sub>J</sub> =25°C  | --   | 35   | --   | ns   |
| I <sub>RRM</sub> | Max. Reverse Recovery Current |  | --   | 2.5  | --   | A    |
| t <sub>rr</sub>  | Reverse Recovery Time         | V <sub>R</sub> =150V, I <sub>F</sub> =30A<br>dI <sub>F</sub> /dt=-200A/µs, T <sub>J</sub> =125°C | --   | 70   | --   | ns   |
| I <sub>RRM</sub> | Max. Reverse Recovery Current |  | --   | 6.8  | --   | A    |

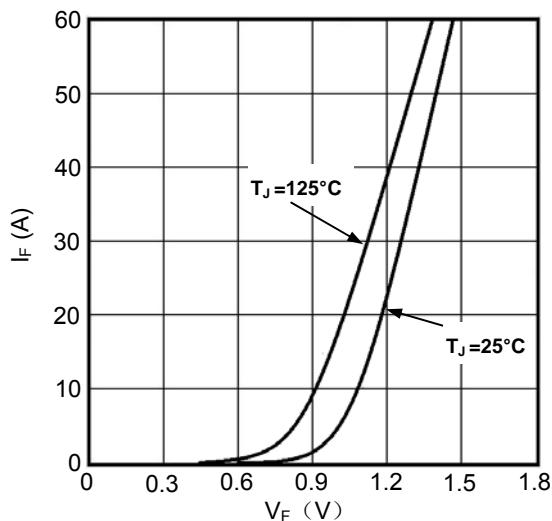


Fig1. Forward Voltage Drop vs Forward Current

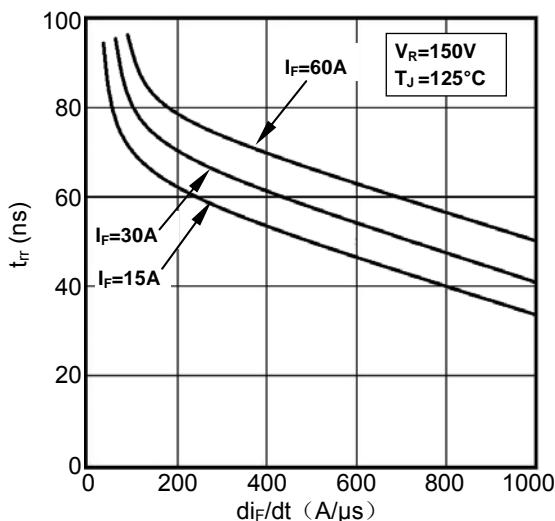
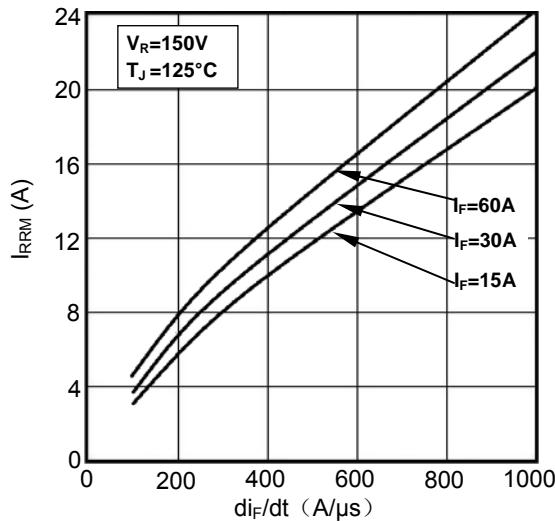
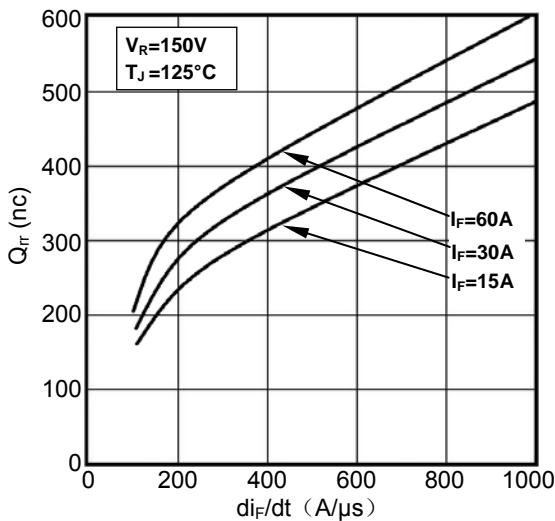
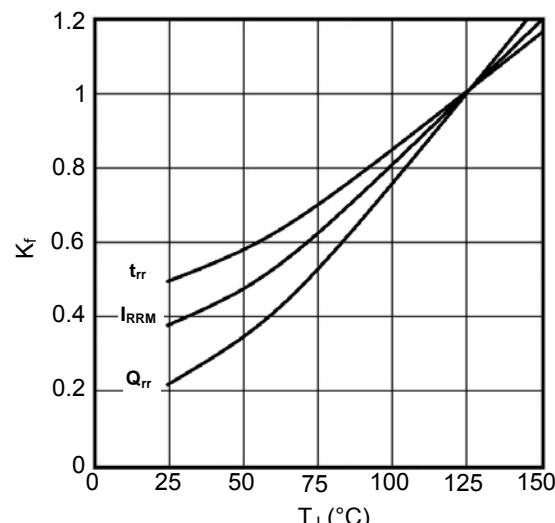
Fig2. Reverse Recovery Time vs  $di_F/dt$ Fig3. Reverse Recovery Current vs  $di_F/dt$ Fig4. Reverse Recovery Charge vs  $di_F/dt$ 

Fig5. Dynamic Parameters vs Junction Temperature

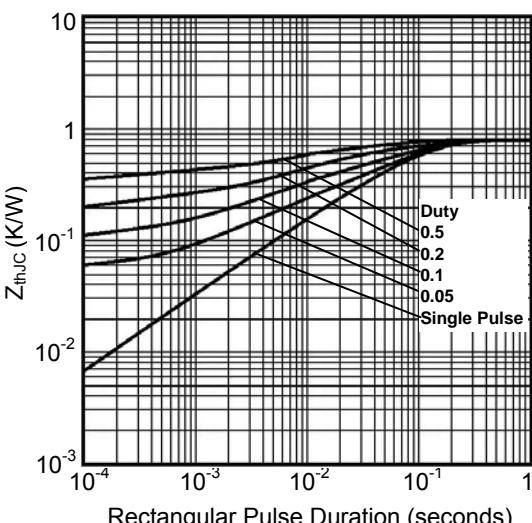


Fig6. Transient Thermal Impedance

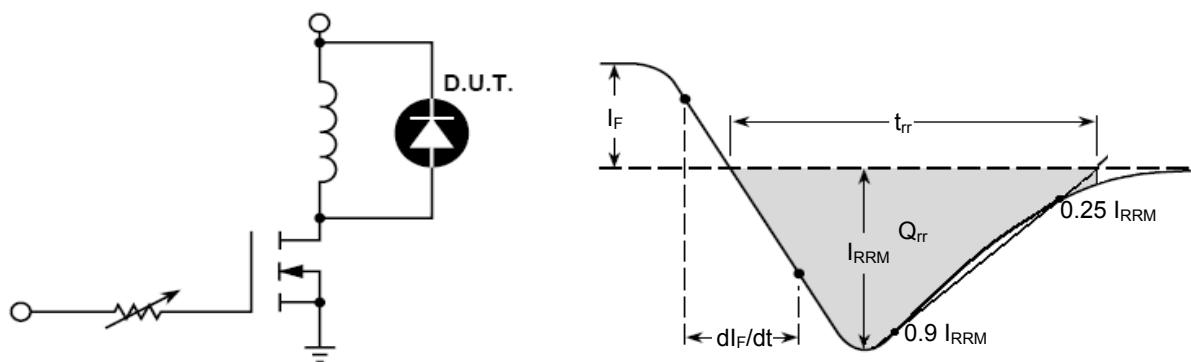
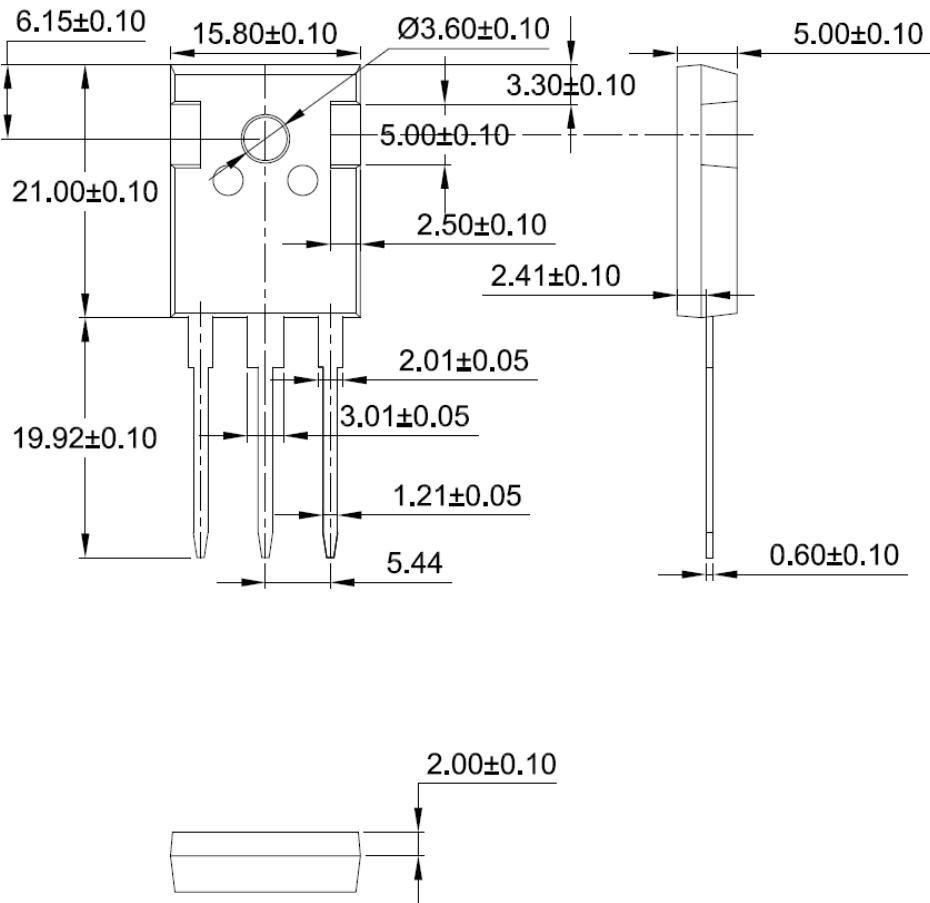


Fig7. Diode Reverse Recovery Test Circuit and Waveform



Dimensions in Millimeters  
Fig8. Package Outline